

Q518D



Features

- Component level MDA test and circuit level ATE test can do in the same platform at the same time to save the man hour in test station.
- Cost effective :integrated MDA module and function module at any time you want to realize your complicated test work.
- Both MDA and ATE automatic switch, additional fixture isolation does not require.
- Security :your already exist function module can integrated as a partial of this system through software or hardware linking. You need not to tell us the detail technique about you products.
- Flexibility: you can bundle any test module from current system easily upon you products innovation. You can update your system just in time.
- Nature graphic simulation interface, so that you can debug your test program very easily.
- Oracle Data base architecture, users can program their special facilities/functions by their own without modify the system software.

Function:

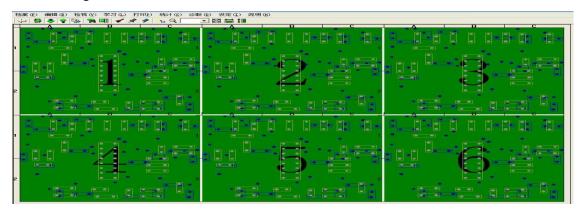
- 1.Data base architecture, the test results data write to data base to realize central data acquisition, analysis, remote monitoring facilities.
- 2. Supply a DC constant voltage constant current from a programmable power supply (PPS) to DUT to protect the damage through the test.
- 3.Supply AC220V/110V AC from AC source, voltage, frequency and trip protect is essential.
- 4.Dynamic test: test the voltage, current, waveform, frequency at the test point you assigned, and simulation the test activities through dry contact relay to realize the fully automatic test.
- 5. Support 14sets per card 0.5ms 1 Amp high speed dry contact relay card, maximum 42 sets contact relay to realize the manipulation of the test.
- 6.Support 10 sets per card maximum 30 sets 16A/250V high current dry relay contact facility to explain the additional power module for this system.
- 7.Flexible architecture: combine 3/6/11 wires measurement, you can choose the best solution for your test need
- 8.Digital input function:32 channels per switch card, maximum 256 channels digital input to monitoring the test data on the DUT.

Console:

1. Edit screen



2. Plate diagram



Device configuration							
Test points		Standard Configuration	256 Channels	Maximu m Points	1024	Maximum Expanded Charge Points 65536 Customized	
Channel board	CMOS +Relay	128 channels per channel board					
Isolation points		10 per test step, automatic learning isolation					
Source	Conventional signal Source	DCV:±10mV~±7.5V OR 15V ACV:10mVpp~10Vpp ACDVI:10u~20mA					
	Test frequency	100、1000、10K、100KHz、2MHz、(50Hz)					
Test step		No limit					
Test frequency		component test: 1ms~40ms O/S test: 05 s /102					
Test scope	Resistance	$0.052\sim100$ M Ω (2-wire type) 1% \sim 5% (4-wire type) 10m Ω					
	Capacitance	1pF~40mF±2%~5%					
	Inductance	1uH~50H±2%~5%					
	Diode	0.1~9V±1%~3%					
	Zener diode	0.1~15V±1%~3%					
	Transistor	Vce saturation voltage and B value are tested in three stages					
	field-effect transistor	Vds.Cds&Rd (on)					
	Optical coupler and power failure organ	The four terminals test their on-voltage or resistance					
Impedance series-parallel connection		Using multi-frequency test and phase separation method (8 ~82 degrees)					
Polarity of Electrolytic Capacitor and Leakage Detection Technology		Three-terminal characteristic discrimination comparison technology test and two-terminal leakage current test					
Feature selection function	Microresistor (4-wire Type)	Minimum 50mQ (4-wire) ± 10mΩ					

	DRMode	Detectable diode or IC forward parallel leakage and empty soldering	
	Key press	During the key test, the program is suspended, and manual operation is used	
	function	to detect whether the key is good or bad	
	Automatic stamp	Test PASS or Fail automatic stamping equipment	
	Monitor placement	Monitoring placement orientation (PASS or Fail shunt)	
	Multi- pressure bed	Multi-or double-press system	
	First pass yield surveillance	When the first pass yield < X% is the alarm bell and < Y% is the alarm bell, stop the line inspection	
	Graphic function	Board View)& Automatic Production of Board View	
	Connecting board function	The linking board is automatically unfolded & the sub-board is selected and tested & the linking board is automatically detected	
	Test data archiving	Save the test data selection items & barcode scanning	
	SFIS	ShineWave SFIS、Sajet SFIS、Off-Line SFIS	
	re protection nction	Infrared protection function	
Operating system		Windows XP	
Computer configuration		CPU: Dual Core 2.8+Memory: 2GB/ Hard Disk: 1000G+G/Monitor: 19 "Monitor	
Printer		Epson Bill printer	
Machine size (length * width * height)		1000mm*750mm*1600MM (Machine size can be customized according to customer requirements)	
Circuit board dimensions		500mmX350mm	
Air pressure demand		3~6Kgs/cm2	
Working Environment- Power Supply		Temperature 0-45 degrees, humidity 10-90%&AC220V	